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### **HDD reliability in CE environment**

This presentation will focus on the subject of drive reliability in the consumer environment. We will discuss some real field data and compare CE and PC environments in terms of failure rate and overall reliability. The tentative title for the presentation would be "HDD reliability in CE environment".

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Dr. Andrei Khurshudov is a Senior Manager in charge of Reliability Technology at Samsung Information Systems America. His field of expertise is reliability and technology of magnetic hard disk drives. Prior to his work at Samsung, Dr. Khurshudov focused on the development of server-class drives at the IBM Corporation and Hitachi Global Storage Technologies.

Dr. Khurshudov received his Ph.D in Mechanical Engineering from the A.A. Blagonravov Mechanical Engineering Research Institute of the Russian Academy of Sciences. He has published over 30 technical papers in referred journals, holds several US patents, and has published a book entitled "The essential guide to computer data storage: from floppy to DVD" (2001).

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